

# Experimental Designs for Accelerated Degradation Tests Based on Gamma Process Models

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## Abstract

Accelerated degradation tests (ADTs) are used to provide an accurate estimation of lifetime properties of highly reliable products within a relatively short testing time. In this regard, data from particular tests at high levels of stress (e.g., temperature, voltage, or vibration) are extrapolated, through a physically reasonable statistical model, to obtain estimates of lifetime quantiles at normal stress levels. The gamma process is a natural model for estimating the degradation increments over the degradation path, which exhibit a monotone and strictly increasing degradation pattern. In this work, we derive optimal experimental designs for repeated measures ADTs with single and multiple failure modes where the observational times are assumed to be known and fixed. The primary degradation path is assumed to follow a Gamma process where a generalized linear model (GLM) is derived in order to represent the observational data and facilitate obtaining an optimal design. The optimal design is obtained by minimizing the asymptotic variance of the estimator of the  $p$ -th quantile of the failure time distribution at the normal use conditions. In order to avoid components damages and further experimental costs that depends on high stress levels, a penalty function is used to derive a penalized locally optimal design.

*Keywords:* Accelerated degradation test, gamma process model, linear mixed effects model, the multiplicative algorithm, locally optimal design.

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## 1. Introduction

Along with the rapid advances of industrial technologies, the companies are forced to manufacture highly reliable products in order to compete in the industrial market. During the design stage, it is extremely significant to assess the reliability related properties of the product. One of the proposed methods to handle this issue is accelerated life testing (ALT). However, it is difficult to obtain enough failure time data to satisfy the requirement of ALT because of the high-reliable property of products. Hence, ADT is suggested in order to give estimations in relatively short periods of time about the life time and reliability of the system under study.

ADT might be divided into three classes, constant stress ADT (CSADT), step stress ADT (SSADT) and progressive ADT. In our model, we consider the optimal planning of CSADT where the testing units are divided into groups where each group is tested under distinct stress combination.

Numerous researches have considered the implementation of ADT to provide reliability estimations.

Tsai et al. (2016) derived an algorithm-based optimal ADT procedure by minimizing the asymptotic variance of the MLE of the mean time to failure of a product, where the sample size and termination time of each run of the ADT at a constant measurement frequency were determined. Zhang et al. (2015) suggest an analytical optimal ADT design method for more efficient reliability demonstration by minimizing the asymptotic variance of decision variable in reliability demonstration under the constraints of sample size, test duration, test cost, and predetermined decision risks. Considering linear mixed effects model (LMEM), Weaver and Meeker (2014) utilized also the minimum asymptotic variance criterion to develop optimal design as well as compromise design plans for accelerated degradation tests. Further, Ankenman et al. (2003) provide D-optimal experimental designs for the estimation of fixed effects and two variance components, in the presence of nested random effects. The authors show that the designs when the samples are distributed as uniformly as possible among batches result in D-optimal designs for maximum likelihood estimation. For the non-linear case, Bogacka et al. (2017) present D-optimal experimental designs for non-linear mixed effects models,

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where a categorical factor with covariate information is a design variable combined with another design factor. Moreover, Sinha and Xu (2011) study the performance of the locally D-optimal sequential designs for analyzing generalized linear mixed models. The authors demonstrate that one could attain considerable gain in efficiency from the maximum likelihood estimators when data are augmented with the sequential design scheme rather than the much simpler uniform design scheme.

Considering GP models, Pan and Balakrishnan (2011) introduce a system with two  $s$ -dependent performance characteristics and that their degradation can be expressed by GP. They propose a bivariate Birnbaum Saunders distribution its marginal distributions to approximate the reliability function. In addition, Pan and Sun (2014) introduce reliability model of the degradation products with two performance characteristics based on GP, and then present the corresponding SSADT model. Next, under the constraint of total experimental cost, the optimal settings such as sample size, measurement times, and measurement frequency are obtained by minimizing the asymptotic variance of the estimated 100 qth percentile of the products lifetime distribution. In order to predict the lifetime of the population from ADT, Wang et al. (2015) consider GP with a time transformation and random effects. They present a deducing method for determining the relationships between the shape and scale parameters of GP and accelerated stresses. Duan and Wang (2019) discuss optimal design problems for CSADT based on gamma processes with fixed effect and random effect. They prove that, for D-optimality, V-optimality and A-optimality criteria, optimal CSADT plans with multiple stress levels degenerate to two stress-level test plans only using the minimum and maximum stress levels under model assumptions. Lim (2015) develops statistical methods for optimal designing ADT plans under the total experimental cost constraint and assuming that the degradation characteristic follows GP. In addition, the author derives compromise plans to provide means to check the adequacy of the assumed acceleration model.

ADT with the presence of Competing failure modes is an important reliability area to be addressed. Therefore, the study of the statistical inference of ADT with competing failures is of great significance. Li, Xiaoyang and Jiang, Tongmin (2009) utilize drift Brownian motion to model SSADT problem with competing failure mechanisms. Zhang et al. (2014) use the copula function to construct the statistically dependent relationship between the margin distributions of the competing failure modes and their joint distributions in ALT. In addition, the authors present a simple engineering-based multi-dimensional copula construction method applied in the statistical inference for ALT with statistically dependent competing failure modes. Further, Bunea and Mazzuchi (2006) present a Bayesian framework for the analysis of ALT data with multiple competing failure modes. Considering the probability of traumatic shocks, Zhao et al. (2018) propose two- and three-level numerically optimal ADT plans for products suffering from both degradation failures and random shock failures. The authors assume the degradation to be modeled by a Wiener process where the arrival process of random shocks is assumed to follow a non-homogeneous Poisson process. In addition, Haghghi and Bae (2015) introduce a modeling approach to simultaneously analyze linear degradation data and traumatic failures with competing risks in an SSADT experiment. Moreover, methodology for ALT planning when there are two or more independent failure modes was discussed by Pascual (2007). The author assumes that the failure modes have respective latent failure times, and the minimum of these times corresponds to the product lifetime. The latent failure times are assumed to be  $-$ independently distributed Weibull with known, common shape parameter. Considering accelerated destructive degradation tests (ADDT), Shi and Meeker (2014) propose methods to find unconstrained and constrained optimum test plans for competing risk applications under a V-optimality criterion that aim to minimize the large-sample approximate variance of a failure-time distribution quantile at use conditions. The authors consider linearly degraded response models with an application for an adhesive bond.

The rest of this chapter is organized as follows. In Section 2, we obtain optimal experimental design for a univariate gamma model. In Section 3, we introduce a c-optimal design for ADT with multiple failure modes considering GP and LMEM. Finally, some concluding remarks are made in Section 4.

## 2. ADT with a univariate gamma model

The gamma process is a natural stochastic model for degradation processes in which degradation is assumed to occur gradually over time in a sequence of independent increments. In this section, we assume that the testing unit has a single dependent failure mode where the degradation path is characterized by a gamma model with a standardized time scale  $\tau = \sqrt{\log t}$ . In addition, it is assumed that the normalized stress level  $x$  is a scalar and, accordingly, the design region  $\mathbf{X} = [0, 1]$ .

The subsequent sections clarify the approximation of the gamma model with GLM. In addition, we explain the derivation of the corresponding information matrix in order to obtain an algorithm-based optimal experimental design with respect to the asymptotic variance of some quantile of the failure time distribution.

### 2.1. Model description

Considering the properties of GP, we assume that the degradation increments during the observational intervals  $[\tau_j, \tau_{j-1}]$  of length  $\Delta_j = \tau_j - \tau_{j-1}$ ,  $j = 1, \dots, k$ , say  $Y_j$ , are independently gamma distributed with the following density function

$$f(Y_j) = \frac{Y_j^{\eta(x)\Delta_j - 1}}{\nu^{\eta(x)\Delta_j} \Gamma(\eta(x)\Delta_j)} \exp\left(-\frac{Y_j}{\nu}\right) \quad (2.1)$$

where  $\eta(x)$  is a known function that is expressed in terms of the standardized stress level  $x$  and  $\eta(x)\Delta_j$  is the shape parameter that describes the accelerated stress effect on the degradation path. In addition,  $\nu$  is the scale parameter that does not depend on the stress level  $s$  nor on the time interval and is assumed to be previously known. It is further assumed that the observational intervals are known and fixed for all stress level, i.e.  $\Delta_j = \Delta \forall j$ . In addition,  $\eta(x)$  can be related to the standardized stress level  $x$  as

$$\eta(x) = \exp(\lambda_1 + \lambda_2 x). \quad (2.2)$$

Now, the degradation path at stress level  $x$  during a single increment can be sufficiently described using the mean value  $E(Y)$  with a linear regression type linear predictor  $\lambda_1 + \lambda_2 x$  and a logarithmic link function as

$$E(Y) = \mu(x) = \nu \Delta \eta(x) = \nu \Delta \exp(\lambda_1 + \lambda_2 x). \quad (2.3)$$

By applying GLM formulation,  $\mu(x)$  is a non-linear function of the linear predictor  $\mathbf{f}(x)^T \boldsymbol{\theta}$  of the form  $\mu(x) = g^{-1}(\mathbf{f}(x)^T \boldsymbol{\theta})$  with a link function  $g(\cdot) = \ln(\cdot)$ ,  $\mathbf{f}(x) = (1, x)^T$  and  $\boldsymbol{\theta} = (\tilde{\lambda}_1, \lambda_2)^T$  where  $\tilde{\lambda}_1 = \ln \nu + \ln \Delta + \lambda_1$ .

Since the approximation above corresponds to a normalized stress  $x$ . It is important to note that several experiments are performed at varying stress levels.

### 2.2. Information matrix

For the previously described univariate model, we assume that the degradation test is conducted over a sample of  $n$  independent statistical units with potentially different stress settings  $x$ . Further, in order to obtain the corresponding information matrix, we first introduce the design measure  $\boldsymbol{\xi}$  which is defined on the design region  $X$  and is expressed as

$$\boldsymbol{\xi} = \begin{pmatrix} x_1 & \dots & x_S \\ \omega_1 & \dots & \omega_S \end{pmatrix}, \quad (2.4)$$

where  $S$  is the number of potential support points  $x_1, \dots, x_S \in X$  and  $\omega_1, \dots, \omega_S \geq 0$  are the corresponding proportions of replications,  $\sum_{s=1}^S \omega_s = 1$ .

Thus, assuming that we consider here a single observation test, i.e.  $k = 1$ , the standardized Fisher information matrix for  $\boldsymbol{\theta}$  which corresponds to the design measure  $\boldsymbol{\xi}$ , is defined as

$$\mathbf{M}(\boldsymbol{\xi}, \boldsymbol{\theta}) = \sum_{s=1}^S \omega_s q(\mathbf{f}(x_s)^T \boldsymbol{\theta}) \mathbf{f}(x_s) \mathbf{f}(x_s)^T \quad (2.5)$$

where  $q(\mathbf{f}(x_s)^T \boldsymbol{\theta}) = \frac{\left(\frac{\partial \mu(x_s)}{\partial \mathbf{f}(x_s)^T \boldsymbol{\theta}}\right)^2}{\mu(x_s) \nu} = \frac{\exp(\tilde{\lambda}_1 + \lambda_2 x_s)}{\nu}$  and  $\mu(x_s) \nu = \text{var}(Y|x_s)$ .

Assuming that a single increment interval is considered, we define the function  $h(x) = z = \mathbf{f}(x)^T \boldsymbol{\theta} = \tilde{\lambda}_1 + \lambda_2 x$  with induced design variable  $z$  such that  $\mathbf{f}(z) = \mathbf{T} \mathbf{f}(x)$ ,  $\boldsymbol{\theta} = (\mathbf{T}^{-1})^T \boldsymbol{\theta}$  where

$$\mathbf{T} = \begin{bmatrix} 1 & 0 \\ \tilde{\lambda}_1 & \lambda_2 \end{bmatrix}.$$

and  $\mathbf{f}(z)^T \tilde{\boldsymbol{\theta}} = \mathbf{f}(x)^T \boldsymbol{\theta}$ . For further details, see Ford et al. (1992).

Considering the transformed design variable  $z$  that belongs to the induced design region  $\mathbf{Z} = \{\mathbf{f}(x)^T \boldsymbol{\theta} : x \in [0, 1]\}$ , the induced design measure  $\boldsymbol{\xi}_h$  can be defined as

$$\boldsymbol{\xi}_h = \begin{pmatrix} z_1 & \dots & z_S \\ \omega_1 & \dots & \omega_S \end{pmatrix}, \quad (2.6)$$

where  $z_s = \mathbf{f}(x_s)^T \boldsymbol{\theta}$  and  $S$  is the number of potential support points.

Thus, the Fisher information matrix for the resulting standard parameters vector  $\tilde{\boldsymbol{\theta}} = (0, 1)^T$ , considering a design measure  $\boldsymbol{\xi}_h$ , is given by

$$\begin{aligned} \mathbf{M}(\boldsymbol{\xi}_h, \tilde{\boldsymbol{\theta}}) &= \sum_{s=1}^S \omega_s q(\mathbf{f}(z_s)^T \tilde{\boldsymbol{\theta}}) \mathbf{f}(z_s) \mathbf{f}(z_s)^T \\ &= \mathbf{T} \left( \sum_{s=1}^S \omega_s q(\mathbf{f}(x_s)^T \boldsymbol{\theta}) \mathbf{f}(x_s) \mathbf{f}(x_s)^T \right) \mathbf{T}^T \\ &= \mathbf{T} \mathbf{M}(\boldsymbol{\xi}, \boldsymbol{\theta}) \mathbf{T}^T \end{aligned} \quad (2.7)$$

where  $q(z) = \frac{(\frac{\partial \mu(z)}{\partial z})^2}{\mu(z)\nu} = \frac{\mu'(z)^2}{\mu(z)\nu}$  and  $\mu(z)\nu = \text{var}(Y|z)$ .

Following the work of Elfving (1952), we define the symmetric Elfving set for a given set of parameters  $\tilde{\boldsymbol{\theta}} = (0.5, 0.7)^T$ , which is the convex hull of the following set that is also shown in Figure 1.

$$\mathcal{C} = \left\{ \tilde{\mathbf{f}}(z), \quad z \in \mathbf{Z} \right\} \cup \left\{ -\tilde{\mathbf{f}}(z), \quad z \in \mathbf{Z} \right\} \subseteq \mathbb{R}^2 \quad (2.8)$$

where  $\tilde{\mathbf{f}}(z) = \sqrt{\frac{\mu(z)}{\nu}} \mathbf{f}(z)$ .

### 2.3. Failure time distribution

In order to develop our optimality criterion, we derive first a generalized formula of the failure time distribution which will be included later in the optimality criterion at the use condition of stress variables.

Denote  $T$  as the failure time random variable where the failure occurs when the degradation path exceeds a predetermined threshold  $\vartheta$ . Assuming that at time  $\tau = 0$  all units start without any previous degradation, the function of the cumulative failure time distribution can be expressed as

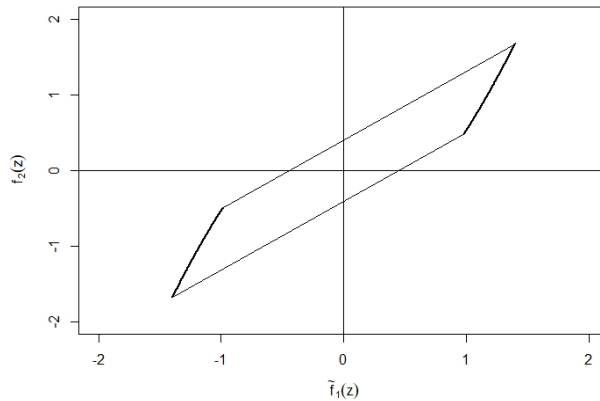


Figure 1: Elfving set for the gamma model, fat lines correspond to  $\tilde{\mathbf{f}}(z)$  (right side) and  $-\tilde{\mathbf{f}}(z)$  (left side).

$$\begin{aligned}
F_T(\tau, x) &= \Pr(T \leq \tau) = \Pr(Y_\tau \geq \vartheta) \\
&= \int_{\vartheta}^{\infty} \frac{y^{\eta(x)\tau-1}}{\nu^{\eta(x)\tau} \Gamma(\eta(x)\tau)} \exp\left(\frac{-y}{\nu}\right) dy \\
&= 1 - \int_0^{\vartheta} \frac{y^{\eta(x)\tau-1}}{\nu^{\eta(x)\tau} \Gamma(\eta(x)\tau)} \exp\left(\frac{-y}{\nu}\right) dy \\
&= 1 - \frac{1}{\Gamma(\eta(x)\tau)} \int_0^{\vartheta\nu} y^{\eta(x)\tau-1} \exp(-y) dy
\end{aligned} \tag{2.9}$$

where  $\vartheta_\nu = \frac{\vartheta}{\nu}$  and  $Y_\tau$  refers to the random process variable with non-decreasing paths in  $\tau$  and gamma distributed marginals.

In this ADT we are interested in failure time quantiles at the normal use condition, i.e.  $x_0$ , where typically  $x_0 \notin X$  and  $x_0 < 0$ . Assuming that  $\eta(x_0)\tau$  is the shape parameter of the gamma process under the normal usage condition, we derive the density function of  $T$  as

$$\begin{aligned}
f_T(\tau, x_0) &= \frac{dF_T(\tau, x_0)}{d\tau} = -\frac{1}{\Gamma(\eta(x_0)\tau)} \int_0^{\vartheta\nu} \eta(x_0) y^{\eta(x_0)\tau-2} \exp(-y) dy \\
&\quad + \frac{\eta(x_0)\zeta(\eta(x_0)\tau)}{\Gamma(\eta(x_0)\tau)} \int_0^{\vartheta\nu} y^{\eta(x_0)\tau-1} \exp(-y) dy.
\end{aligned} \tag{2.10}$$

where  $\zeta(u) = \frac{d\Gamma(u)}{d(u)}$ .

In order to simplify the computations, we will consider an approximate of  $F_T(\tau, x_0)$  with the following Birnbaum-Saunders distribution which is introduced first by Park and Padgett (2005).

$$\begin{aligned}
F_T(\tau, x_0) &= \Phi \left[ \sqrt{\vartheta_\nu} \left( \sqrt{\frac{\eta(x_0)\tau}{\vartheta_\nu}} - \sqrt{\frac{\vartheta_\nu}{\eta(x_0)\tau}} \right) \right] \\
&= \Phi \left[ \frac{1}{\eta^*} \left( \sqrt{\frac{\tau}{\nu^*}} - \sqrt{\frac{\nu^*}{\tau}} \right) \right]
\end{aligned} \tag{2.11}$$

where  $\eta^* = \frac{1}{\sqrt{\vartheta_\nu}}$  and  $\nu^* = \frac{\vartheta_\nu}{\eta(x_0)}$ .

Consequently, the density function is expressed as

$$\begin{aligned}
f_T(\tau, x_0) &= \frac{\partial F_T(\tau, x_0)}{\partial \tau} \\
&= \frac{\sqrt{\vartheta_\nu}}{2} \left( \sqrt{\frac{\eta(x_0)}{\vartheta_\nu \tau}} + \frac{1}{\tau} \sqrt{\frac{\vartheta_\nu}{\eta(x_0)\tau}} \right) \times \phi \left[ \frac{1}{\eta^*} \left( \sqrt{\frac{\tau}{\nu^*}} - \sqrt{\frac{\nu^*}{\tau}} \right) \right].
\end{aligned} \tag{2.12}$$

#### 2.4. Optimality criterion

For the case of obtaining an optimal design for ADT based on the single measure information matrix defined in 2.2 as well as the failure time distribution introduced in 2.3, we consider an optimality criterion of the minimum asymptotic variance for the maximum likelihood estimator of a failure time quantile, i.e.  $\text{AVar}(\tau_\gamma)$ , where  $\tau_\gamma$  is the  $\gamma$ th quantile of the unit's failure time distribution  $F_T(\tau_\gamma, x_0)$ . This criterion is commonly used in planning degradation tests when experimenters are interested in accurately estimating some reliability properties of a system over its life cycle. Considering that the minimum asymptotic variance optimality criterion, which is close to c-optimality criterion, is equivariant under the previously used transformations of the form  $x \rightarrow z$  and  $\theta \rightarrow \theta$  where  $x$  is mapped to  $z$  resulting an induced design region  $\mathbf{Z}$ . Note that these transformations can lead to an optimal experimental design independently of  $\theta$ . Accordingly, the optimality criteria can

be expressed as

$$\begin{aligned}\min \text{AVar}(\tau_\gamma) &= \frac{\mathbf{m}^T \mathbf{M}(\boldsymbol{\xi}, \boldsymbol{\theta})^{-1} \mathbf{m}}{[f_T(\tau_\gamma, x_0)]^2} \\ &= \frac{\mathbf{m}_h^T \mathbf{M}(\boldsymbol{\xi}_h, \tilde{\boldsymbol{\theta}})^{-1} \mathbf{m}_h}{[f_T(\tau_\gamma, x_0)]^2}\end{aligned}\quad (2.13)$$

where  $\mathbf{m} = \left( \frac{\partial F_T(\tau_\gamma, x_0)}{\partial \lambda_1}, \frac{\partial F_T(\tau_\gamma, x_0)}{\partial \lambda_2} \right)^T$ ,  $\mathbf{m}_h = (\mathbf{T}^{-1})^T \mathbf{m}$ , and the elements of  $\mathbf{m}_h$  are derived as

$$\mathbf{m}_h = \begin{bmatrix} m_1 - m_2 \left( \frac{\lambda_1}{\lambda_2} \right) \\ \frac{m_2}{\lambda_2} \end{bmatrix} \quad (2.14)$$

where

$$\begin{aligned}m_1 &= \frac{\sqrt{\vartheta_\nu}}{2} \left( \sqrt{\frac{\tau_\gamma}{\vartheta_\nu \eta(x_0)}} + \frac{1}{\eta(x_0)} \sqrt{\frac{\vartheta_\nu}{\eta(x_0) \tau_\gamma}} \right) \times \phi \left[ \frac{1}{\eta^*} \left( \sqrt{\frac{\tau_\gamma}{\nu^*}} - \sqrt{\frac{\nu^*}{\tau_\gamma}} \right) \right] \\ m_2 &= \frac{\sqrt{\vartheta_\nu}}{2} \left( x_0 \sqrt{\frac{\tau_\gamma}{\vartheta_\nu \eta(x_0)}} + \frac{x_0}{\eta(x_0)} \sqrt{\frac{\vartheta_\nu}{\eta(x_0) \tau_\gamma}} \right) \times \phi \left[ \frac{1}{\eta^*} \left( \sqrt{\frac{\tau_\gamma}{\nu^*}} - \sqrt{\frac{\nu^*}{\tau_\gamma}} \right) \right]\end{aligned}$$

### 2.5. Numerical Example

Based on the work of Torsney and Martín-Martín (2009), the multiplicative algorithm will be used to obtain a locally optimal design  $\boldsymbol{\xi}^*$  with respect to the standardized stress parameter  $x$  and the parameters vector  $\boldsymbol{\theta} = (0.5, 0.7)^T$ . The algorithm will be applied with a 0.005 increment over the induced design region  $\mathbf{Z} = [0.5, 1.2]$  where a single standardized time increment with length  $\Delta = 0.5$  is considered during the test. Table 1 shows the assumed nominal values of parameters and variables that are adopted to obtain a locally c-optimal design. Considering the median of the failure time distribution  $\tau_{0.5}$ , the gradient vector is calculated for these values to be  $\mathbf{m}_h = (1.432, -0.859)^T$ .

Table 1: Nominal values of a univariate gamma model.

$\lambda_1 = 0.5$	$x_0 = -0.60$
$\lambda_2 = 0.7$	$\tau_{0.5} = 1.09$
$\nu = 1.7$	$\vartheta_\nu = 1.17$

The resulting optimal design  $\boldsymbol{\xi}_h^*$  that corresponds to the induced design region  $\mathbf{Z}$  is given as

$$\boldsymbol{\xi}_h^* = \begin{pmatrix} 0.5 & 1.2 \\ 0.699 & 0.301 \end{pmatrix} \quad (2.15)$$

Accordingly, the optimal design  $\boldsymbol{\xi}^*$  based on the standardized design region  $\mathbf{X}$  is calculated as

$$\boldsymbol{\xi}^* = \begin{pmatrix} 0 & 1 \\ 0.699 & 0.301 \end{pmatrix}. \quad (2.16)$$

which means that about 70 percent of the observations should be made at the lowest stress level  $x = 0$  and the remaining 30 percent should be made at the highest stress level  $x = 1$ . Furthermore, Elfving's theorem can be applied to insure the optimality of the obtained design  $\boldsymbol{\xi}^*$ . The numerically obtained gradient vector  $\mathbf{m}_h$  is plotted over the Elfving set  $\mathcal{C}$  in figure 2 which shows that the gradient vector intersects with the boundary of the Elfving convex hull at the point  $C$  which lies on the connecting line between  $A = \tilde{\mathbf{f}}(h(0))$  and  $-B = -\tilde{\mathbf{f}}(h(1))$ . Assuming that  $w$  refers to the Euclidean distance (ED) between  $A$  and  $-B$ , then we can obtain the weights  $\omega_1 = \frac{w_1}{w}$  and  $\omega_2 = \frac{w_2}{w}$  where  $w_1$  is ED between  $C$  and  $-B$  and  $w_2$  is ED between  $C$  and  $A$ .

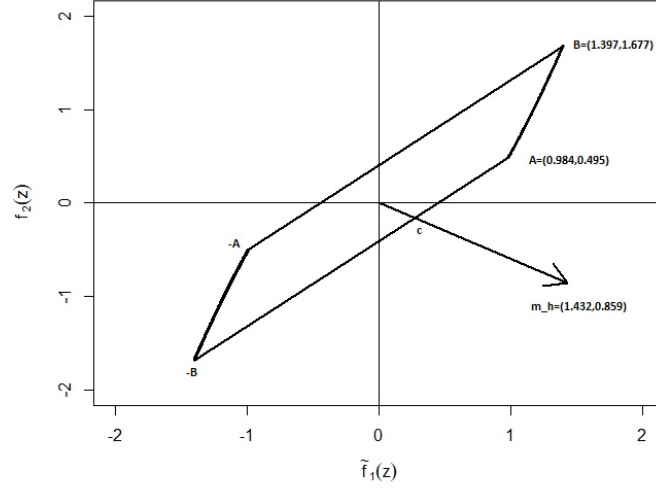


Figure 2: Intersection between Elfving set and the gradient vector.

Accordingly, the corresponding optimal design  $\xi_h^*$  is defined as

$$\xi_h^* = \begin{pmatrix} 0 & 1 \\ \omega_1 = 0.7 & \omega_2 = 0.3 \end{pmatrix}. \quad (2.17)$$

Considering the definition of  $\mathcal{C}$  in 2.8, the points  $A$  and  $B$  correspond to the values 0 and 1 of the standardized design region  $\mathbf{X}$ , respectively. Thus, the optimal design  $\xi_h^*$  coincides with the numerically obtained design  $\xi^*$ . Actually it can be shown that for the case of extrapolation where  $x_0 < 0$  the intersection point  $C$  lies always on the connecting line between  $A$  and  $-B$ . Hence, for the present model the optimal design always uses only the lowest and the highest stress level.

### 3. ADT with multiple failure modes and repeated measures

The majority of the existing research in ADT focuses on obtaining optimal experimental designs assuming that the system undergoes a single failure mode. However, many engineering systems may have multiple modes that can lead to a system failure. Accordingly, We propose an optimal design for ADT considering two degradation modes that can result a failure where both modes are independent and do not have interactive effect. In this model, we assume that a failure occurs when at least one degradation path exceeds the corresponding critical threshold. It is also assumed that the corresponding accelerating stress variables for our model  $\mathbf{x} = (x_1, x_2)$ , which are transformed from the actual stress variables  $(s_1, s_2)$ , are defined over the design region  $\mathbf{X} = [0, 1]^2$ . In the subsequent sections we formulate the two degradation paths where the first one is expressed with LMEM and the later is expressed with GP model. Further, we utilize the multiplicative algorithm to get optimal design based on the optimality criterion of the minimum asymptotic variance of some quantile of the failure time distribution.

#### 3.1. First failure mode formulation

In our model, the first degradation path is expressed by a linear model with a random intercept, which coincides with the fixed effect model derived in 2.2 when  $k = 1$ , and corresponds to the standardized accelerating variable  $\mathbf{x} = (x_1, x_2)$  where these variables are respectively transformed from the actual accelerated stresses  $(s_1, s_2)$ . In order to simplify our presentation, we define first the fixed effects regression function as well as the parameters vector regarding unit  $i$  during the  $j$ -th observation as  $\mathbf{f}_1(\tau_j, \mathbf{x}_i) = (x_{i1}, x_{i2}, x_{i1}\tau_j, x_{i2}\tau_j)^T$  and  $\boldsymbol{\delta} = (\delta_1, \delta_2, \delta_3, \delta_4)^T$ , respectively.

random intercept  $k=1$  coincides with fixed effect model of 1.2.2

Accordingly, the degradation path which is expressed with the random variable  $Y_1$  for unit  $i$  during the  $j$ -th observation is defined as.

$$Y_{1ij} = \mathbf{f}_1(\tau_j, \mathbf{x}_i)^T \boldsymbol{\theta}_{1i} + \varepsilon_{ij} \quad (3.1)$$

Where

$$\mathbf{f}_1(\tau_j, \mathbf{x}_i) = (1, \tilde{\mathbf{f}}_1(\tau_j, \mathbf{x}_i)^T)^T \text{ and } \boldsymbol{\theta}_{1i} = (b_i, \boldsymbol{\delta}^T)^T \text{ such that } \mathbf{x}_i \in \mathbf{X} = [0, 1]^2, j = 1, \dots, k, i = 1, \dots, n. \quad (3.2)$$

Further, we assume that random effects parameter as well as random error parameter are independently and normally distributed as  $b_i \sim N(\beta, \sigma_b^2)$ ,  $\varepsilon_{ij} \sim N(0, \sigma_\varepsilon^2)$  and  $\tau$  is the transformed time variable as  $\tau = \sqrt{\log t}$ . Denote  $T_1$  as the random variable of the failure time distribution regarding the first failure mode. Further, we assume that a failure occurs when the degradation path exceeds a predetermined threshold  $\vartheta_1$ . Hence, as in subsection 2.3, we assume that the corresponding failure distribution function regarding equation 3.1 is defined as

$$F_{T_1}(\tau_j, \mathbf{x}_i) = 1 - \Phi \left[ \frac{\vartheta_1 - \tilde{\mathbf{f}}_1(\tau_j, \mathbf{x}_i)^T \boldsymbol{\delta} - \beta}{\sigma_b} \right] \quad (3.3)$$

where  $\vartheta_1$  indicates the critical threshold with respect to the first failure mode.

#### 3.2. Second failure mode formulation

Considering the second failure mode, it is assumed that the degradation increments, say  $Y_2$ , which depends only on the first standardized stress variable  $x_1$  of the testing unit, is modelled with a GP function which is a different generalization of the model described in 2.1 that coincides when  $k = 1$ . Hence, the strictly increasing degradation increments  $Y_{2ij}$  for unit  $i$  during the  $j$ -th increment is gamma distributed with the following density function

$$\mathbf{f}_2(Y_{2ij}) = \frac{Y_{2ij}^{\eta(x_{i1})\Delta - 1}}{\nu^{\eta(x_{i1})\Delta} \Gamma(\eta(x_{i1})\Delta)} \exp\left(-\frac{Y_{2ij}}{\nu}\right) \quad (3.4)$$

where  $\eta(x_1) = \exp(\lambda_1 + \lambda_2 x_1)$ ,  $\eta(x_1)\Delta$  is the shape parameter that describes the accelerated stress effect on the degradation path and  $\nu$  is the scale parameter which does not depend on  $x_1$  and assumed to be a known constant. Denote  $T_2$  as the random variable of the failure time distribution



regarding the second failure mode. Assuming that  $Y_2 = 0$  for  $\tau = 0$ , the failure time distribution function for the second degradation function defined in equation 3.4 can be expressed as

$$\begin{aligned}
F_{T_2}(\tau_j, x_{i1}) &= \Pr(T_2 \leq \tau_j) = \Pr(Y_{2\tau_j} \geq \vartheta_2) \\
&= \int_{\vartheta_2}^{\infty} \frac{1}{\nu^{\eta(x_{i1})\tau_j} \Gamma(\eta(x_{i1})\tau_j)} y_2^{\eta(x_{i1})\tau_j - 1} \exp\left(\frac{-y_2}{\nu}\right) dy_2 \\
&= \frac{1}{\Gamma(\eta(x_{i1})\tau_j)} \int_{\tilde{\vartheta}_2}^{\infty} y_2^{\eta(x_{i1})\tau_j - 1} \exp(-y_2) dy_2 \\
&= \frac{\Gamma(\eta(x_{i1})\tau_j, \tilde{\vartheta}_2)}{\Gamma(\eta(x_{i1})\tau_j)}
\end{aligned} \tag{3.5}$$

where  $\tilde{\vartheta}_2 = \frac{\vartheta_2}{\nu}$  and  $\Gamma(\alpha, \beta)$  is the incomplete gamma function which is defined as, see Wang et al. (2015).

$$\Gamma(g, k) = \int_k^{\infty} x^{g-1} \exp(-x) dx \tag{3.6}$$

### 3.3. Failure time distribution

Subsequently, we derive here the joint failure time distribution of the testing unit where  $T$  indicates the joint failure time variable. Based on the assumption that the two marginal failure times  $T_1$  and  $T_2$  are independent.  $T$  is obtained by either the first failure mode or the second one, whichever is earlier, i.e.,  $T = \min\{T_1, T_2\}$ . Considering the Birnbaum-Saunders approximation of  $F_{T_2}(\tau, x_1)$  which is previously explained in section 2.3, the joint distribution function of  $T$  can be expressed as

$$\begin{aligned}
F_T(\tau, \mathbf{x}) &= \Pr(\min\{T_1, T_2\} \leq \tau) \\
&= 1 - [1 - F_{T_1}(\tau, \mathbf{x})][1 - F_{T_2}(\tau, x_1)] \\
&= 1 - \Phi\left[\frac{\vartheta_1 - \tilde{\mathbf{f}}_1(\tau, \mathbf{x})^T \boldsymbol{\delta} - \beta}{\sigma_b}\right] \left[1 - \Phi\left[\sqrt{\tilde{\vartheta}_2} \left(\sqrt{\frac{\eta(x_1)\tau}{\tilde{\vartheta}_2}} - \sqrt{\frac{\tilde{\vartheta}_2}{\eta(x_1)\tau}}\right)\right]\right]
\end{aligned} \tag{3.7}$$

In order to derive the joint log likelihood function, we define the  $9 \times 1$  joint parameters vector  $\boldsymbol{\theta} = (\boldsymbol{\theta}_2^T, \tilde{\boldsymbol{\theta}}_1^T)^T$  where  $\boldsymbol{\theta}_2 = (\lambda_1, \lambda_2)^T$ ,  $\boldsymbol{\sigma} = (\sigma_{b_0}, \sigma_\varepsilon)^T$  and  $\tilde{\boldsymbol{\theta}}_1 = (\boldsymbol{\theta}_1^T, \boldsymbol{\sigma}^T)^T$ . In addition,  $\boldsymbol{\theta}_1$  is the location parameters vector  $(\beta, \delta_1, \delta_2, \delta_3, \delta_4)^T$ . Thus, the joint log likelihood function of  $\boldsymbol{\theta}$ , which is utilized to obtain the maximum likelihood estimators MLEs of the unknown parameters, say  $\hat{\boldsymbol{\theta}}$ , can be expressed as

$$\begin{aligned}
\ell(\boldsymbol{\theta}) &= \sum_{s=1}^S \sum_{i=1}^{n_s} \sum_{j=1}^k \left[ -\frac{y_{2sij}}{\nu} + (\eta(x_{1s})\tau_j - 1) \log y_{2sij} - \log \Gamma(\eta(x_{1s})\tau_j) - \eta(x_{1s})\tau_j \log \nu \right] \\
&\quad - \frac{1}{2} \sum_{s=1}^S \sum_{i=1}^{n_s} \left[ \log(\det(\mathbf{D})) + \left[ (\mathbf{y}_{1si} - \mathbf{f}_1(\boldsymbol{\tau}, \mathbf{x}_s))^T \boldsymbol{\theta}_1 \right]^T \mathbf{D}^{-1} \left( \mathbf{y}_{1si} - \mathbf{f}_1(\boldsymbol{\tau}, \mathbf{x}_s)^T \boldsymbol{\theta}_1 \right) \right].
\end{aligned} \tag{3.8}$$

Where  $\mathbf{y}_{1si} = (y_{1si1}, \dots, y_{1sik})^T$ ,  $\mathbf{f}_1(\boldsymbol{\tau}, \mathbf{x}_s) = (\mathbf{f}_1(\tau_1, \mathbf{x}_s), \dots, \mathbf{f}_1(\tau_k, \mathbf{x}_s))$  and  $n_s$  refers to number of units to be tested at stress level  $s$ . In addition, we define the time plan  $\boldsymbol{\tau} = (\tau_1, \dots, \tau_k)^T$  which does not depend on neither  $s$  nor  $i$ . Moreover, the variance covariance matrix for each unit is expressed as  $\mathbf{D} = \sigma_b \mathbf{I}_k + \sigma_\varepsilon \mathbf{J}_k$  where  $\mathbf{I}_k$  is the  $k$ -dimensional identity matrix and  $\mathbf{J}_k$  is the  $k \times k$  matrix with all entries equal to 1.

Accordingly, the MLE of the 100  $\gamma^{th}$  quantile of the failure time distribution at the use condition is defined as  $\tau_\gamma = F_T^{-1}(\gamma)$ .

### 3.4. Information matrix

The Fisher information matrix can be defined as the covariance matrix (matrix of second moments) of the vector of first derivatives of  $\ell(\boldsymbol{\theta})$  with respect to the components of  $\boldsymbol{\theta}$ . Moreover, under certain regularity conditions, this is equal to the negative matrix of second derivatives. However, to



### 3.6. Numerical example: A locally optimal design

In this section, we obtain a numerical optimal design by considering a nominal value of the parameter vector  $\theta$ . Based on the optimality criterion defined in equation 3.9, the locally optimal design  $\xi^*$  is defined as

$$\xi^* = \arg \min_{\xi \in \Xi} \left[ \text{AVar}(\hat{\tau}_\gamma) = \frac{\mathbf{m}^T [\mathbf{M}(\xi, \theta)]^{-1} \mathbf{m}}{[f_T(\tau_\gamma, \mathbf{x}_0)]^2} \right] \quad (3.11)$$

Due to the non-linearity of the optimality criterion defined in 3.11 as well as the difficulty to validate the convexity, algorithm-based optimization method will be used to obtain the optimal design. According to the c-optimality criterion, the directional derivative at the design measure  $\xi$  in the direction of the single design measure  $\xi_{\mathbf{x}}$  which puts unit mass at the factor-level combination  $\mathbf{x}$  is expressed as

$$\mathbf{F}(\xi, \xi_{\mathbf{x}}) = \frac{\mathbf{m}^T [\mathbf{M}(\xi, \theta)]^{-1} \mathbf{M}(\xi_{\mathbf{x}}, \theta) [\mathbf{M}(\xi, \theta)]^{-1} \mathbf{m} - \mathbf{m}^T [\mathbf{M}(\xi, \theta)]^{-1} \mathbf{m}}{[f_T(\tau_\gamma, \mathbf{x}_0)]^2} \quad (3.12)$$

where  $\mathbf{M}(\xi_{\mathbf{x}}, \theta)$  is the elementary information matrix at the stress level  $\mathbf{x}$  as defined above and  $\mathbf{M}(\xi, \theta) = \sum_{s=1}^S \omega_s \mathbf{M}(\xi_{\mathbf{x}_s}, \theta)$ .

Considering the general equivalence theorem (GET),  $\xi^*$  is a global optimal design if and only if  $\sup_{0 \leq x \leq 1} \mathbf{F}(\xi^*, \xi_{\mathbf{x}}) = 0$ . In addition, the global optimality of  $\xi^*$  is verified by showing that  $\mathbf{F}(\xi^*, \xi_{\mathbf{x}}) = 0 \forall \mathbf{x}$  in the support points of  $\xi^*$  and  $\mathbf{F}(\xi^*, \xi_{\mathbf{x}_s}) \leq 0$  otherwise.

In order to obtain a numerical optimal design, the multiplicative algorithm with an equidistant grid of 0.08 marginal increments over the standardized design region  $\mathbf{X} = [0, 1]^2$  is developed. The aim of this algorithm is to find the optimal design that minimizes the asymptotic variance of the median of the failure time distribution, which is calculated to be  $\tau_{0.5} = 1.928$ . In addition, it is assumed that all observations were conducted according to the standardized time plan  $\tau = (0, 0.05, 0.1, 0.15, 0.2)$ . For a locally optimal design, table 2 shows the nominal values of parameters and constants which are used to obtain a locally optimal design.

Table 2: Nominal values of the bivariate mixed model.

$\lambda_1 = 0.5$	$\lambda_2 = 0.7$	$x_{1_0} = -0.6$	$x_{2_0} = -0.45$
$\delta_1 = 2.0$	$\delta_2 = 4.1$	$\delta_3 = 0.8$	$\delta_4 = 0.85$
$\nu = 1.7$	$\beta = 4.7$	$\vartheta_1 = 10.3$	$\vartheta_2 = 3.55$

The resulting optimal design  $\xi^*$  that corresponds to the standardized design region  $\mathbf{X}$  is given as

$$\xi^* = \left( \left( \begin{matrix} (0, x_{2i}) \\ \omega_1^* = 0.0542 \end{matrix} \right)_{i=1}^{13}, \left( \begin{matrix} (1, x_{2i}) \\ \omega_2^* = 0.0227 \end{matrix} \right)_{i=1}^{13} \right) \quad (3.13)$$

where  $x_{2i} = 0 + 0.08(i - 1) \in \{0.00, 0.08, \dots, 0.96\}$ .

### 3.7. Example: Sensitivity analysis

In the previous section, it is stated that the obtained optimal design is locally optimal on the basis of a nominal value of the parameter vector  $\hat{\theta}$ . As the values of this vector are subject to potential changes corresponding to inaccurate specification of the true parameter, a sensitivity analysis is conducted to study the behaviour of the (possibly rounded) optimal experimental design  $\hat{\xi}^*$  under various parameters specifications. The expression of rounded optimal design refers to the potential transfer of weights from support points with low weights in  $\xi^*$  to support points with higher weights in  $\xi^*$ , see Dorfleitner and Klein (1999).

When considering the first model which corresponds to the linear degradation path, it becomes obvious that the obtained optimal design  $\xi^*$  is robust against potential changes in the parameter values for  $\theta_1 = (\beta, \delta_1, \delta_2, \delta_3, \delta_4)^T$ .

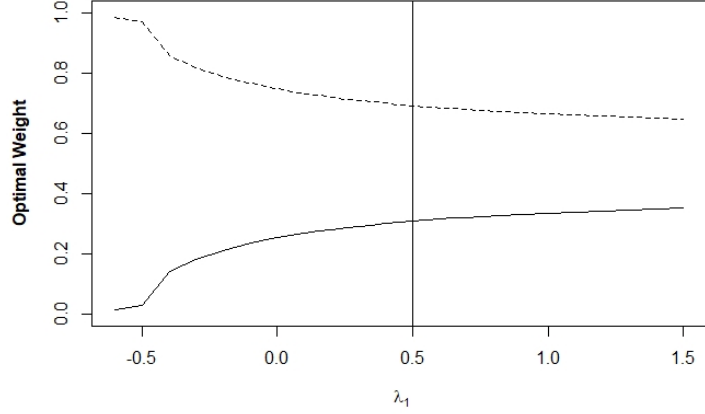


Figure 3: Dependence of the optimal weights on  $\lambda_1$ ,  $\hat{\omega}_1^*$ : dashed line,  $\hat{\omega}_2^*$ : solid line, vertical line:  $\lambda_1 = 0.5$ .

However, the sensitivity analysis procedure may result some support points with relatively low weights in  $\xi^*$  due to changes in the parameter values. As mentioned earlier in this section, the rounding approach will be used to obtain optimal marginal weights  $\hat{\omega}_l^*$ ,  $l = 1, 2$  in  $\xi^*$ . This rounding procedure transfers the weights of the support points with small weights in  $\xi^*$  to the support with higher weights. The following figures indicate the dependence of the optimal weights on the parameters in the Gamma model, i.e.  $\theta_2 = (\lambda_1, \lambda_2)^T$ , with respect to the nominal values given in table 2.

Let  $\hat{\omega}_l^* = \sum_{i=1}^{13} \hat{\omega}_i^*$ ,  $l = 1, 2$ , figure 3 indicates noticeable changes of the optimal weights ( $\hat{\omega}_1^*$ ,  $\hat{\omega}_2^*$ ) over the range of  $\lambda_1$  when the other values in  $\theta$  are kept fixed to the nominal values given in table 2. It can be seen that  $\hat{\omega}_1^*$  is always larger than  $\hat{\omega}_2^*$  despite the gradual increase of the values of  $\hat{\omega}_2^*$  where  $\hat{\omega}_1^*$  refers to the total optimal weight on the design points with  $x_1 = 0$  and  $\hat{\omega}_2^*$  refers to the total optimal weight on the design points with  $x_1 = 1$ .

Further, given that  $\lambda_1$  is kept fixed to its nominal value in table 2, figure 4 exhibits a strong dependence of the optimal weights on  $\lambda_2$ . First, it should be noted that  $\hat{\omega}_1^* = \hat{\omega}_2^*$  for  $\lambda_2 = 0$ , i.e. when the stress variable  $x_1$  does not have impact on the degradation of the second failure mode. Furthermore, figure 4 indicates a gradual increase of  $\hat{\omega}_1^*$  over the range of  $\lambda_2$  as opposed to gradual decrease of  $\hat{\omega}_2^*$  that clarifies the obvious dependence of the marginal weights on  $\lambda_2$ .

As mentioned earlier, the obtained optimal designs  $\hat{\omega}_l^*$  are rounded to coincide with the optimal design  $\omega_l^*$  regarding the obtained support points. Therefore, the efficiency of the rounded designs are calculated in order to judge the robustness of these designs. Figures 5 and 6 show the computed efficiency of  $\hat{\xi}^*$  over ranges of  $\lambda_1$  and  $\lambda_2$ , respectively, where the efficiency is determined according to the following equation

$$\text{eff}(\hat{\xi}^*) = \frac{\text{AVar}(\hat{\tau}_\gamma; \xi^*)}{\text{AVar}(\hat{\tau}_\gamma; \hat{\xi}^*)} = \frac{\mathbf{m}^T \left[ \mathbf{M}(\xi^*, \theta) \right]^{-1} \mathbf{m}}{\mathbf{m}^T \left[ \mathbf{M}(\hat{\xi}^*, \theta) \right]^{-1} \mathbf{m}}. \quad (3.14)$$

The obtained results indicate that the rounded optimal designs  $\hat{\xi}^*$  are robust in the sense that the design  $\text{eff}(\hat{\xi}^*)$  is quite high over a wide range of parameter values for  $\lambda_1$  and  $\lambda_2$ .

#### 4. Concluding remarks

It is known that the rapid advances of industrial technologies force the companies to manufacture highly reliable products in order to compete in the industrial market. Hence, ADT is suggested in order to give estimations in relatively short periods of time about the life time and reliability of the system under study. However, most of the literature deals with this issue only by considering a single failure mode, which may not be appropriate in some cases. Here, based on multiple failure modes, an optimal experimental design for ADT is proposed. It is assumed that the marginal failure modes are independent and uncorrelated. The multiplicative algorithm is utilized to obtain optimal experimental design for our model. The sensitivity analysis shows adequate robustness of the rounded

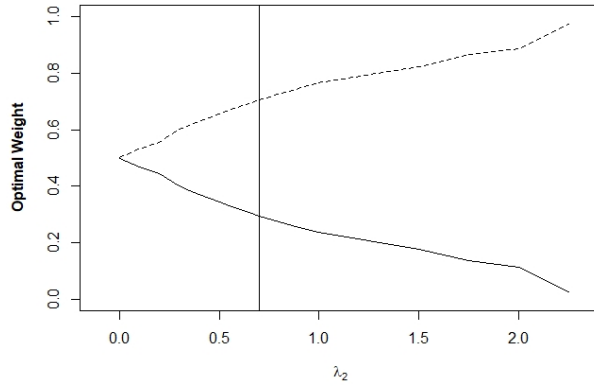


Figure 4: Dependence of the optimal weights on  $\lambda_2$ ,  $\hat{\omega}_1^*$ : dashed line,  $\hat{\omega}_2^*$ : solid line, vertical line:  $\lambda_2 = 0.7$ .

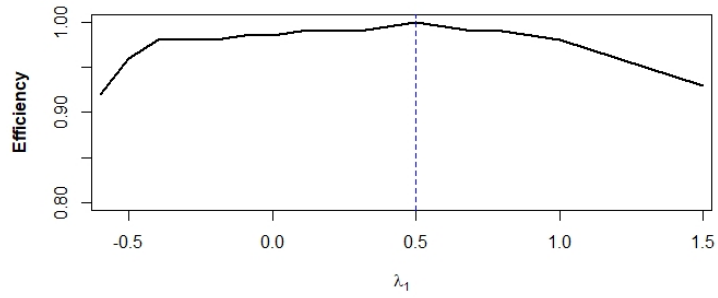


Figure 5: Efficiency of  $\hat{\xi}^*$  in dependence on  $\lambda_1$ , vertical line: maximum efficiency when  $\lambda_1 = 0.5$ .

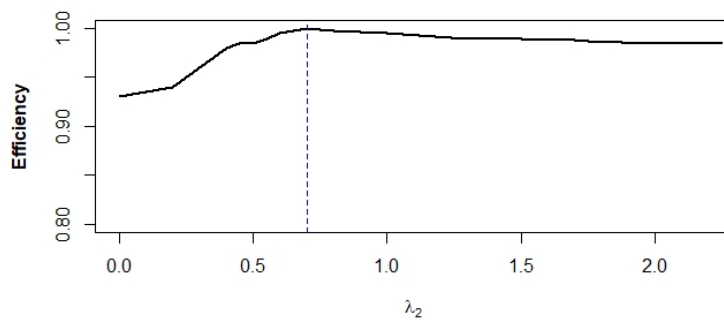


Figure 6: Efficiency of  $\hat{\xi}^*$  in dependence on  $\lambda_2$ , vertical line: maximum efficiency when  $\lambda_2 = 0.7$ .

optimal designs over the parameters range. In this work, we have considered GP and LMEM as the marginal degradation models of this ADT. However, the results can be extended to other marginal failure modes. For example, one failure mode could be modelled by a Wiener process, while the other could be described by a inverse Gaussian process.

## Appendix

The elements of the information matrix  $\mathbf{M}(\boldsymbol{\xi}, \boldsymbol{\theta})$  in subsection 3.4 are derived as

$$\begin{aligned}\frac{1}{n}\mathbf{E}\left(-\frac{\partial^2\ell(\boldsymbol{\theta}, \mathbf{y})}{\partial\lambda_1^2}\right) &= \sum_{s=1}^S \omega_s \left(\sum_{j=1}^k (\eta(x_{1s})\tau_j)^2 \zeta_1(\eta(x_{1s})\tau_j)\right), \quad \zeta_1(u) = \frac{\partial^2\Gamma(u)}{\partial(u)^2} \\ \frac{1}{n}\mathbf{E}\left(-\frac{\partial^2\ell(\boldsymbol{\theta}, \mathbf{y})}{\partial\lambda_1\partial\lambda_2}\right) &= \sum_{s=1}^S \omega_s \left(\sum_{j=1}^k (\eta(x_{1s})\tau_j)^2 \zeta_1(\eta(x_{1s})\tau_j)\right) x_{1s} \\ \frac{1}{n}\mathbf{E}\left(-\frac{\partial^2\ell(\boldsymbol{\theta}, \mathbf{y})}{\partial\lambda_2^2}\right) &= \sum_{s=1}^S \omega_s \left(\sum_{j=1}^k (\eta(x_{1s})\tau_j)^2 \zeta_1(\eta(x_{1s})\tau_j)\right) x_{1s}^2 \\ \frac{1}{n}\mathbf{E}\left(-\frac{\partial^2\ell(\boldsymbol{\theta}, \mathbf{y})}{\partial\boldsymbol{\theta}_1^2}\right) &= \sum_{s=1}^S \omega_s \mathbf{f}_1(\boldsymbol{\tau}, \mathbf{x}_s) \mathbf{D}^{-1} \mathbf{f}_1(\boldsymbol{\tau}, \mathbf{x}_s)^T,\end{aligned}$$

Finally, the entries in the gradient vector  $\mathbf{m}$  used in equation 3.9 are derived as

$$\begin{aligned}m_1 &= \left[ \Phi\left(\frac{\vartheta_1 - \tilde{\mathbf{f}}_1(\tau_\gamma, \mathbf{x}_0)^T \boldsymbol{\delta} - \beta}{\sigma_b}\right) \frac{\sqrt{\tilde{\vartheta}_2}}{2} \left(\sqrt{\frac{\tau_\gamma}{\tilde{\vartheta}_2 \eta(x_{10})}} + \frac{1}{\eta(x_{10})} \sqrt{\frac{\tilde{\vartheta}_2}{\eta(x_{10}) \tau_\gamma}}\right) \phi\left(\sqrt{\tilde{\vartheta}_2} \left(\sqrt{\frac{\eta(x_{10}) \tau_\gamma}{\tilde{\vartheta}_2}} - \sqrt{\frac{\tilde{\vartheta}_2}{\eta(x_{10}) \tau_\gamma}}\right)\right) \right], \\ m_2 &= x_{10} \left[ \Phi\left(\frac{\vartheta_1 - \tilde{\mathbf{f}}_1(\tau_\gamma, \mathbf{x}_0)^T \boldsymbol{\delta} - \beta}{\sigma_b}\right) \frac{\sqrt{\tilde{\vartheta}_2}}{2} \left(\sqrt{\frac{\tau_\gamma}{\tilde{\vartheta}_2 \eta(x_{10})}} + \frac{1}{\eta(x_{10})} \sqrt{\frac{\tilde{\vartheta}_2}{\eta(x_{10}) \tau_\gamma}}\right) \phi\left(\sqrt{\tilde{\vartheta}_2} \left(\sqrt{\frac{\eta(x_{10}) \tau_\gamma}{\tilde{\vartheta}_2}} - \sqrt{\frac{\tilde{\vartheta}_2}{\eta(x_{10}) \tau_\gamma}}\right)\right) \right], \\ m_3 &= - \left[ \left(1 - \Phi\left(\sqrt{\tilde{\vartheta}_2} \left(\sqrt{\frac{\eta(x_{10}) \tau_\gamma}{\tilde{\vartheta}_2}} - \sqrt{\frac{\tilde{\vartheta}_2}{\eta(x_{10}) \tau_\gamma}}\right)\right)\right) \times \frac{-1}{\sigma_b} \phi\left(\frac{\vartheta_1 - \tilde{\mathbf{f}}_1(\tau_\gamma, \mathbf{x}_0)^T \boldsymbol{\delta} - \beta}{\sigma_b}\right) \right], \\ m_4 &= - \left[ \left(1 - \Phi\left(\sqrt{\tilde{\vartheta}_2} \left(\sqrt{\frac{\eta(x_{10}) \tau_\gamma}{\tilde{\vartheta}_2}} - \sqrt{\frac{\tilde{\vartheta}_2}{\eta(x_{10}) \tau_\gamma}}\right)\right)\right) \times \frac{-x_{10}}{\sigma_b} \phi\left(\frac{\vartheta_1 - \tilde{\mathbf{f}}_1(\tau_\gamma, \mathbf{x}_0)^T \boldsymbol{\delta} - \beta}{\sigma_b}\right) \right], \\ m_5 &= - \left[ \left(1 - \Phi\left(\sqrt{\tilde{\vartheta}_2} \left(\sqrt{\frac{\eta(x_{10}) \tau_\gamma}{\tilde{\vartheta}_2}} - \sqrt{\frac{\tilde{\vartheta}_2}{\eta(x_{10}) \tau_\gamma}}\right)\right)\right) \times \frac{-x_{20}}{\sigma_b} \phi\left(\frac{\vartheta_1 - \tilde{\mathbf{f}}_1(\tau_\gamma, \mathbf{x}_0)^T \boldsymbol{\delta} - \beta}{\sigma_b}\right) \right], \\ m_6 &= - \left[ \left(1 - \Phi\left(\sqrt{\tilde{\vartheta}_2} \left(\sqrt{\frac{\eta(x_{10}) \tau_\gamma}{\tilde{\vartheta}_2}} - \sqrt{\frac{\tilde{\vartheta}_2}{\eta(x_{10}) \tau_\gamma}}\right)\right)\right) \times \frac{-x_{10} \tau_\gamma}{\sigma_b} \phi\left(\frac{\vartheta_1 - \tilde{\mathbf{f}}_1(\tau_\gamma, \mathbf{x}_0)^T \boldsymbol{\delta} - \beta}{\sigma_b}\right) \right], \\ m_7 &= - \left[ \left(1 - \Phi\left(\sqrt{\tilde{\vartheta}_2} \left(\sqrt{\frac{\eta(x_{10}) \tau_\gamma}{\tilde{\vartheta}_2}} - \sqrt{\frac{\tilde{\vartheta}_2}{\eta(x_{10}) \tau_\gamma}}\right)\right)\right) \times \frac{-x_{20} \tau_\gamma}{\sigma_b} \phi\left(\frac{\vartheta_1 - \tilde{\mathbf{f}}_1(\tau_\gamma, \mathbf{x}_0)^T \boldsymbol{\delta} - \beta}{\sigma_b}\right) \right].\end{aligned}$$

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